

机器模型静电放电试验报告

MM TEST REPORT

委托公司 : Shanghai Belling Corp.,Ltd.

Company

公司地址 : 810 Yi Shan Road., Shanghai, China

Address

产品名称 : BL3085(I47)

Sample name

委托日期 : 2022 年 2 月 7 日

Date Received

完成日期 : 2022 年 2 月 14 日

Date Tested

实验室认证体系 (TESTING LABORATORY IS APPROVAL BY) :

证书编号 : IECQ-L DEKRA 17.0004-01

IECQ Certificate of Approval No.: IECQ-L DEKRA 17.0004-01 For Independent

实验室证明事项 (WE HEREBY CERTIFY THAT) :

对于本报告所载之测试项目及结果, 实验室保证由训练合格之专业技术人员负责执行, 并忠实及完整将各项试验结果记录于报告内。

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

	名称 (Name)	签名 (Signature)	日期 (Date)
检测员 Inspector	赵前璐 Qianlu zhao	赵前璐	2022 年 2 月 12 日
报告审核人 Report reviewer	陈清珑 Larry Chen	陈清珑	2022 年 2 月 14 日
报告批准人 Approver	李鹏云 Smile Li	李鹏云	2022 年 2 月 14 日

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1. 本报告内容以任何方式翻印或复印部份者无效。

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2. 本报告仅对检送样品负责, 且分离使用无效。

This report refers only to the specimen(s) submitted to test, and is invalid if used otherwise.

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This report is ONLY valid with the examination seal and signature of this institute.

4. 样品保存自报告签发日起 30 天。

The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant



报 告 内 容

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1 讯息 (INFORMATION)

1.1 案件讯息 (CASE INFORMATION)

试验样品 Test Sample	批次号 LOT NO.	封装 Package	数量 Quantity
BL3085(I47)	I4715230PP	SOP8	7 pcs

1.2 试验设备说明 (DESCRIPTION OF TEST EQUIPMENT)

项目 Items	设备/编号 Equipment/No.	型号 Model	校准有效期 Calibration validity
1	0008189	KEYTEK ZAPMASTER 7/4	2022年7月4日

1.3 环境条件 (AMBIENCE CONDITION)

标准要求温度 Required temperature	25 ⁺³ ₋₅ °C	实际温度 Actual temperature	22.7~23.1°C
标准要求相对湿度 Required relative humidity	55± 10 %RH	实际湿度 Actual humidity	51.9~55.9%RH

1.4 参考文件 (REFERENCE DOCUMENT)

项目 Items	依据标准 Standards
1	JEDEC EIA/JESD22-A115

1.5 测试要求 (TEST REQUIREMENT)

VCC TO GND (+/-)
IO TO GND (+/-)
IO TO VCC (+/-)
IO TO IO (+/-)
Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V, 650V, 700V, 750V, 800V
VCC TO GND (+/-)
IO TO GND (+/-)
IO TO VCC (+/-)
IO TO IO (+/-)
Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V
VCC TO GND (+/-)
IO TO GND (+/-)
IO TO VCC (+/-)
IO TO IO (+/-)
Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V

地址 (Address): 中国上海浦东新区金丰路 455 号 (2 幢厂房北面车间的西首部的物业, 7 幢厂房北半部分的物业)
No.455 Jinfeng Rd, New District Pudong, Shanghai, China (North west side of the 2nd building; north side of 7th building.)

电话 (Tel): 86-21-61910691, 传真 (Fax): 86-21-64069790

网址 (web): <http://www.chinaisti.com>

REFERENCE DOCUMENT : JEDEC EIA/JESD22-A115

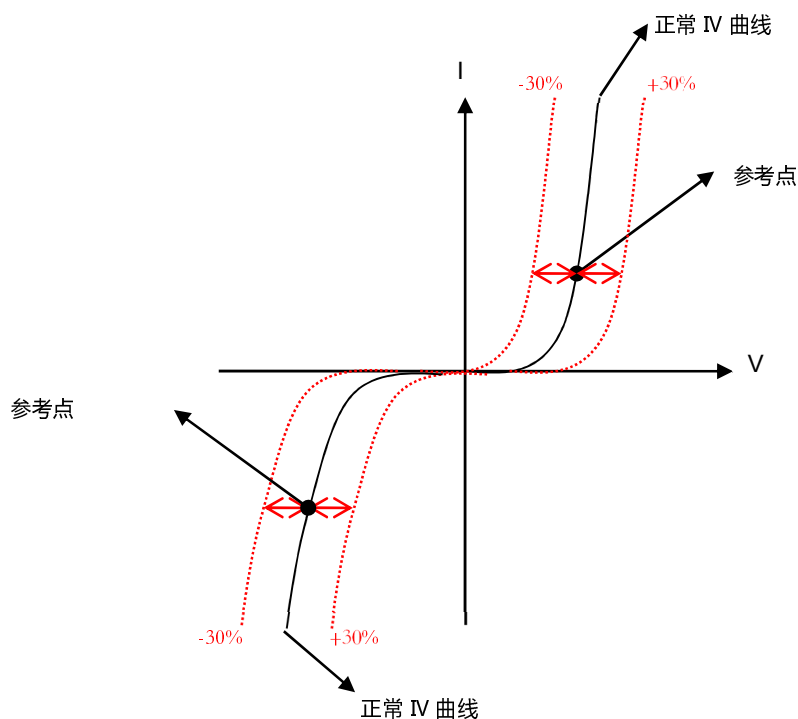
Zap 3 pulse(s), Interval: 1.0 Sec.

TEST VOLTAGE : 200V~800V, Step: 50V(±); 200V~600V, Step: 50V(±);
200V~550V, Step: 50V(±);

SAMPLE QUANTITY : 7 pcs

FAILURE CRITERIA : ±30% voltage shift at reference point before/after zapping
(Reference Only)

※ Failure Judgment: Voltage shift over ±30% at reference point.



2 试验结果 (TEST RESULTS)

2.1 结果汇总 (SUMMARY)

Test Model : MM	ESD Sensitivity Passed : <u>±550V</u>		JEDEC EIA/JESD22-A115 Classification Class : <u>C</u>
Test condition	Sample Quantity	Passed Volts	Class A : < 200V. Class B : ≥ 200V , <400V Class C : ≥ 400V
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V, 650V, 700V, 750V, 800V	1	+/-600V	
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V	1	+/-550V	
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V	5	+/-550V	

Group	Pins
GND	5
IO	1-4,6-7
VCC	8

2.2 测试数据 (TEST DATA)

No	1
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V, 650V, 700V, 750V, 800V	
Tested Pins	Sample No. & Failed Volt
	#M01
1	FAIL(650V)
2	FAIL(800V)
3	FAIL(650V)
4	FAIL(800V)
6	PASS(800V)
7	PASS(800V)
8	FAIL(700V)

No	2
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V, 600V	
Tested Pins	Sample No. & Failed Volt
	#M02
1	FAIL(600V)
2	PASS(600V)
3	PASS(600V)
4	PASS(600V)
6	PASS(600V)
7	PASS(600V)
8	PASS(600V)

No	3				
VCC TO GND (+/-) IO TO GND (+/-) IO TO VCC (+/-) IO TO IO (+/-) Step:200V, 250V, 300V, 350V, 400V, 450V, 500V, 550V					
Tested Pins	Sample No. & Failed Volt				
	#M03	#M04	#M05	#M06	#M07
1	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
2	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
3	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
4	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
6	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
7	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)
8	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)	PASS(550V)

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